

Accepted Manuscript

A pattern recognition approach to transistor array parameter variance

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PII: S0378-4371(18)30087-6
DOI: <https://doi.org/10.1016/j.physa.2018.02.011>
Reference: PHYSA 19131

To appear in: *Physica A*

Received date: 3 September 2017
Revised date: 22 November 2017

Please cite this article as: L.da F. Costa, F.N. Silva, C.H. Comin, A pattern recognition approach to transistor array parameter variance, *Physica A* (2018), <https://doi.org/10.1016/j.physa.2018.02.011>

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Highlights

1. A systematic, quantitative analysis of the properties of bipolar transistors in a same integrated circuit (IC) is presented.
2. It is shown that transistors from the same IC have, on average, 1/20 of the variability in their parameters than transistors from different ICs.
3. The relative variation among devices from different ICs can be large enough to justify customized design for more critical applications.

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